





Power MOSFETS

DATASHEET

LM30025NAK8A

N-Channel
Enhancement Mode MOSFET

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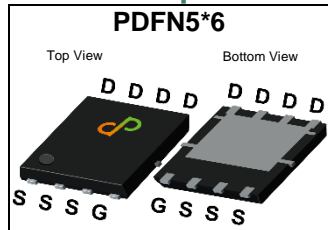


Quality Management Systems

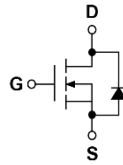
ISO 9001:2015 Certificate

N-Channel Enhancement Mode MOSFET

Pin Description



Symbol



Product Summary

Symbol	N-Channel	Unit
V _{DSS}	30	V
R _{DS(ON)-Max}	2.5	mΩ
ID	115	A

Feature

- Low R_{dson} and low conduction loss
- Surface mount package
- Reliable and Rugged
- ROHS Compliant & Halogen-Free

Applications

- DC/DC Converters
- Motor Control

Ordering Information

Orderable Part Number	Package Type	Form	Shipping	Marking
LM30025NAK8A	PDFN5*6	Tape & Reel	5000 / Tape & Reel	30025 □□□□□□

Note : □□□□□□ = Lot Code

Absolute Maximum Ratings (T_J=25°C Unless Otherwise Noted)

Symbol	Parameter	N-Channel	Unit	
V _{DSS}	Drain-Source Voltage	30	V	
V _{GSS}	Gate-Source Voltage	±20		
T _J	Maximum Junction Temperature	150	°C	
T _{STG}	Storage Temperature Range	-55 to 150	°C	
I _S	Diode Continuous Forward Current	T _C =25°C	46	A
I _{DM} ^①	Pulse Drain Current Tested	T _C =25°C	141	A
I _D	Continuous Drain Current	T _C =25°C	115	A
		T _C =100°C	73	
P _D	Maximum Power Dissipation	T _C =25°C	50	W
		T _C =100°C	20	
I _D	Continuous Drain Current	T _A =25°C	25.8	A
		T _A =70°C	20.7	
P _D	Maximum Power Dissipation	T _A =25°C	2.5	W
		T _A =70°C	1.6	
I _{AS} ^②	Avalanche Current, Single pulse	L=0.1mH	45	A
		L=0.5mH	24	
E _{AS} ^②	Avalanche Energy, Single pulse	L=0.1mH	101	mJ
		L=0.5mH	144	

Thermal Characteristics

Symbol	Parameter	Rating	Unit	
R _{θJC}	Thermal Resistance-Junction to Case	Steady State	2.5	°C/W
R _{θJA} ^③	Thermal Resistance-Junction to Ambient	Steady State	50	°C/W

Note ① : Max. current is limited by bonding wire

Note ② : UIS tested and pulse width are limited by maximum junction temperature 150°C

Note ③ : Surface Mounted on 1in² FR-4 board with 1oz

N-Channel Electrical Characteristics (T_J=25°C Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Static Electrical Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =250uA	30	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	V _{DS} =24V, V _{GS} =0V	-	-	1	uA
V_{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250uA	1	1.5	2	V
I_{GSS}	Gate Leakage Current	V _{GS} =±20V, V _{DS} =0V	-	-	±100	nA
R_{DS(ON)}^④	Drain-Source On-state Resistance	V _{GS} =10V, I _{DS} =20A	-	2.1	2.5	mΩ
		V _{GS} =4.5V, I _{DS} =15A	-	2.8	3.6	
gfs	Forward Transconductance	V _{DS} =5V, I _{DS} =20A	-	38	-	S
Dynamic Characteristics[®]						
R_G	Gate Resistance	V _{GS} =0V, V _{DS} =0V, Freq.=1MHz	-	2.6	-	Ω
C_{ISS}	Input Capacitance	V _{GS} =0V, V _{DS} =15V, Freq.=1MHz	-	4242	-	pF
C_{OSS}	Output Capacitance					
C_{rSS}	Reverse Transfer Capacitance					
td(ON)	Turn-on Delay Time	V _{GS} =10V, V _{DS} =15V, I _D =1A, R _{GEN} =2.5Ω	-	33	-	nS
t_r	Turn-on Rise Time					
t_{d(OFF)}	Turn-off Delay Time					
t_f	Turn-off Fall Time					
Q_g	Total Gate Charge	V _{GS} =4.5V, V _{DS} =25V, I _D =14A	-	46	-	nC
Q_g	Total Gate Charge	V _{GS} =10V, V _{DS} =25V, I _D =14A	-	88	-	
Q_{gs}	Gate-Source Charge		-	7.3	-	
Q_{gd}	Gate-Drain Charge		-	24	-	
Source-Drain Characteristics						
V_{SD}^④	Diode Forward Voltage	I _{SD} =15A, V _{GS} =0V	-	0.8	1.1	V
t_{rr}	Reverse Recovery Time	I _F =15A, V _R =0V	-	19.8	-	nS
Q_{rr}	Reverse Recovery Charge	dI _F /dt=100A/μs	-	8.7	-	nC

Note ④ : Pulse test (pulse width≤300us, duty cycle≤2%).

Note ⑤ : Guaranteed by design, not subject to production testing.

N-Channel Typical Characteristics

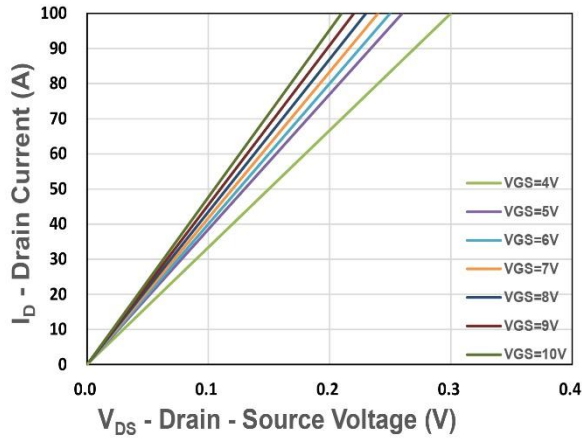


Figure 1. Output Characteristics

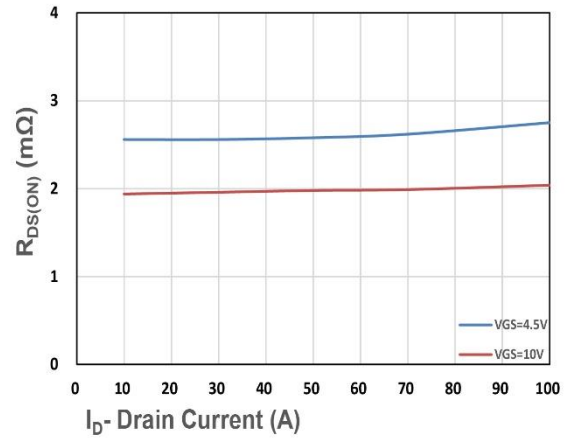


Figure 2. On-Resistance vs. ID

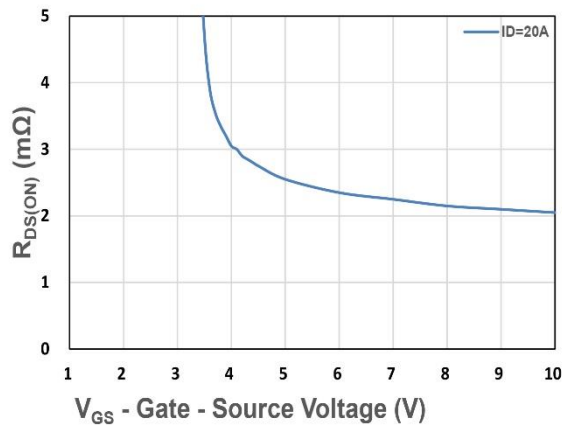


Figure 3. On-Resistance vs. VGS

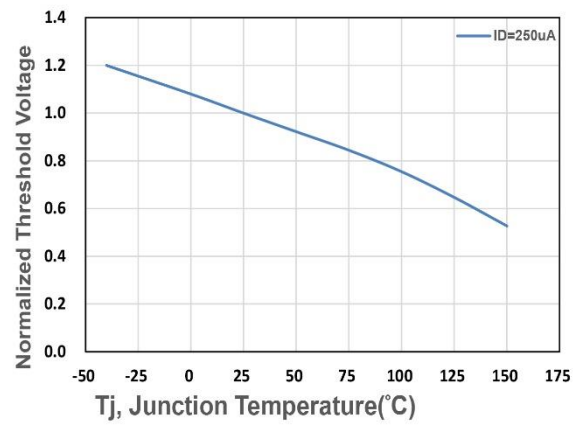


Figure 4. Gate Threshold Voltage

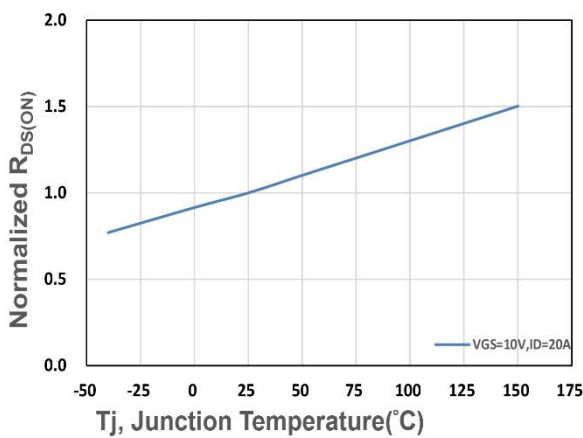


Figure 5. Drain-Source On Resistance

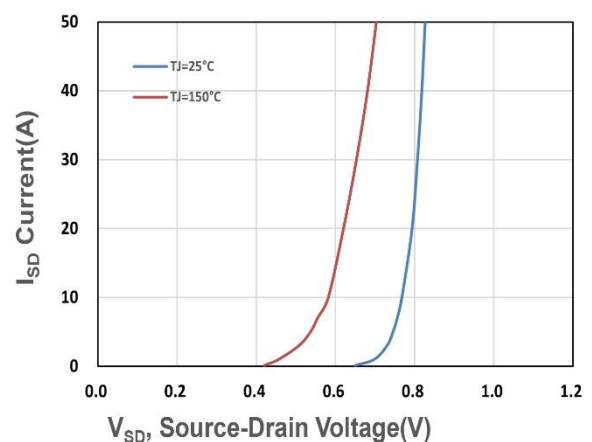


Figure 6. Source-Drain Diode Forward

